

Presenter	Institute	Title of Presentation
Session 1		
Beatriz Noheda	University of Groningen, Netherland	Operando studies of the interplay between ferroelectricity and electrochemistry in all-oxide MIM Hf _{0.5} Zr _{0.5} O ₂ heterostructures
Nick Barrett	CEA-Saclay, Paris, France	Oxygen vacancies in hafnia-based ferroelectric capacitors
Martina Müller	Universität Konstanz, Germany	Defect and interface chemistry in ferroelectric HfO ₂ explored by HAXPES
Session 2		
P. Buragohain/A. Gruverman	UN Lincoln, Nebraska, USA	Nanoscale studies of imprint behavior in ferroelectric La:HfO ₂ capacitors
Alfred Kersch	Univ. of Appl. Sciences, Munich, Germany	Oxygen vacancies in HfO ₂ /ZrO ₂ and impact on the formation of the ferroelectric phase
Lucian Pintilie	NIMP, Magurele, Romania	Structural investigations of HZO films and connection with macroscopic electrical properties
Session 3		
Sayeef Salahuddin	UC Berkeley, California, USA	Ferroelectricity and Negative Capacitance in Ultra-thin Layers of HfO ₂ Based Fluorite Oxides
F. Berg/U. Boettger	RWTH Aachen, Germany	Effects of Moisture in Ferroelectric Switching HfO _x
E. Breyer/S. Slesazeck	NamLab, Dresden, Germany	Compact FeFET circuit building blocks for fast and efficient nonvolatile logic-in-memory
Session 4		
Min Hyuk Park	Pusan National University	Interfacial engineering as a strategy to improve remanent polarization of Hf _{0.5} Zr _{0.5} O ₂ thin film
Anna Chernikova/A. Markeev	MIPT, Moscow, Russia	Electrode-Ferroelectric Interface engineering for improvement of HfO ₂ -based FeRAM memory stacks
Uwe Schroeder	NamLab, Dresden, Germany	Impact of interfacial layers on retention performance of Hf _{0.5} Zr _{0.5} O ₂ based capacitors
Session 5		
Laurent Grenouillet	LETI, Grenoble, France	HfO ₂ -based BEOL-integrated ferroelectric capacitor for ultra low power FeRAM
Jordan Bouaziz/B. Vilquin	Université de Lyon, Lyon, France	Tracking polarization loss and imprint during electrical tests in sputtered TiN/HZO/TiN capacitors
Thanasis Dimoulas	Demokritos, Athens, Greece	Metastable ferroelectricity in scaled HZO induced by depolarizing fields: a phenomenological Landau-Ginzburg approach